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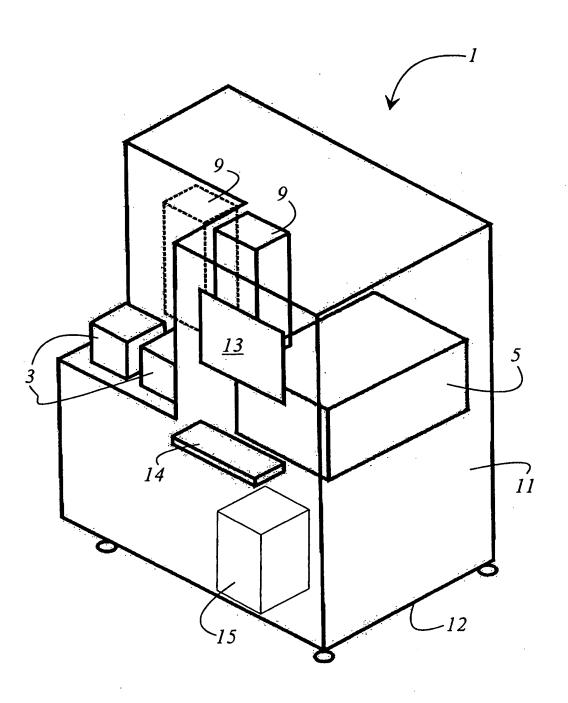


Fig. 1

Title: APPARATUS AND METHOD FOR THIN-LAYER METROLOGY Inventor(s): Matthias SLODOWSKI DOCKET NO.: 016790-0489

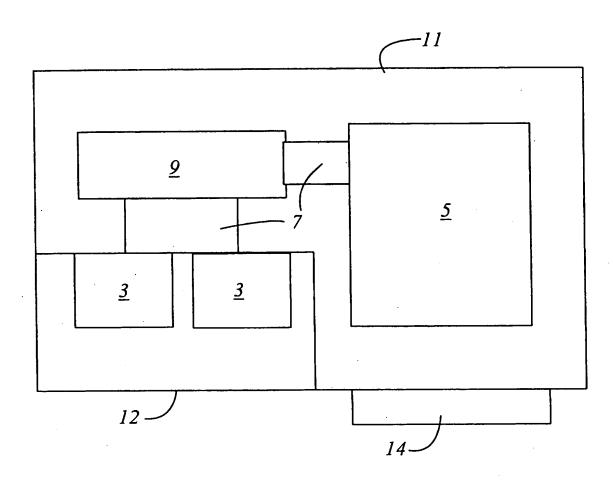


Fig. 2

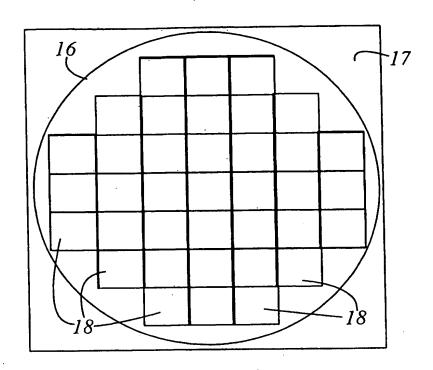
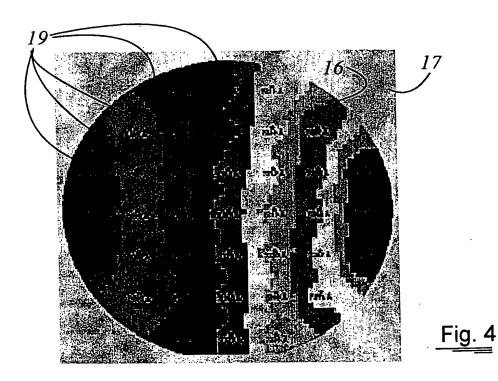
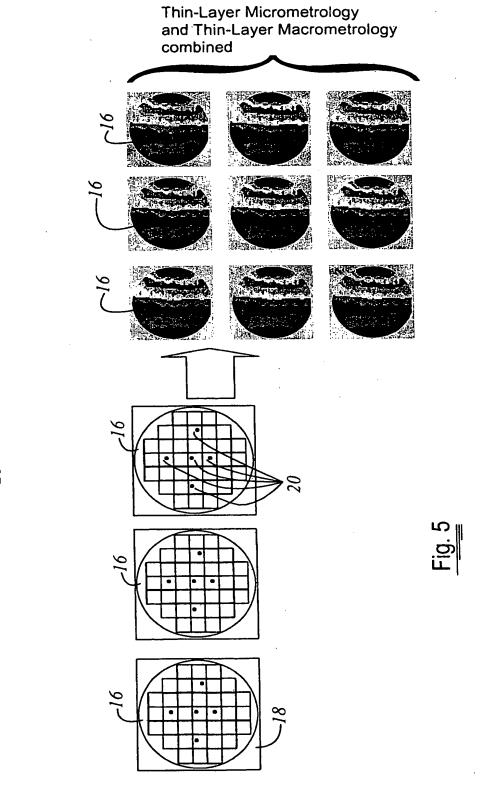
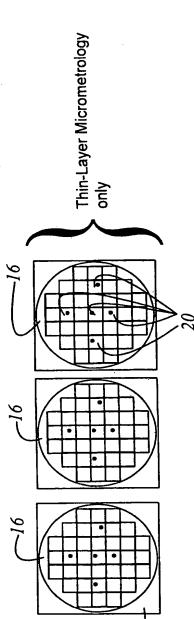


Fig. 3



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